FILTER STRUCTURE, OPTICAL DETECTION SYSTEM, AND OPTICAL DETECTION METHOD

ABSTRACT

A filter, an optical inspection system, and an optical inspection method. The filter includes: a first filter structure configured to filter primary diffraction signals of periodic structural units from an object to be inspected, and a second filter structure configured to filter high-order diffraction spots of the periodic structural units from the object to be inspected. The first filter structure includes at least one filter structure with a closed periphery. In a case where the object to be inspected has the structural units, the closed filter structure is further provided therein with a light-blocking structure connecting any two ends of the closed filter structure. The second filter structure includes a plurality of light-blocking elements arranged in parallel. A projection of a light-blocking element onto a plane where the high-order diffraction spots are located is not less than a diameter of a high-order diffraction spot.

FIG. 9